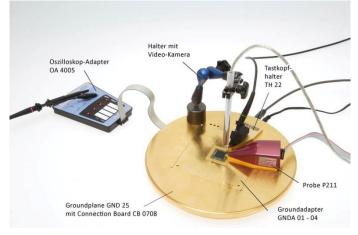


For 20 years Langer EMV-Technik has worked in EMC Suppression

- · We optimize electronics for leading producers worldwide .
- We provide our customers with understandable and affordable solutions for improving their devices.
- We work with customers during development at either the PCB- or the IC levels.
- We develop <u>EMC tools</u> -- practical and timesaving aids for EMC optimization -- for use at the workstation.
- We measure integrated circuits (ICs), specifically the line-conducted and field-coupled EMC parameters, for emission and immunity.
- We measure the EMC parameters of conductors and cables to ascertain its Coupling Inductivity Factor



BISS/IEC standard measurements and immunity and emissions analyses for ICs

We carry out measurements according to BISS/IEC and accompanying analyses of immunity and emission of ICs. With a target orientated EMC analysis we detect weak IC points. With this knowledge the IC developer can make improvements for the product.

IC	CEM 150-1	IC emission m IEC 61967-4	neasurement 150/1 Ohm method acc.
IC	CEM field	IC emission m	neasurement field coupled analysis
IC	CEM Scan	IC emission measurement surface scan method according to IEC 61967-3	
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ICEM SL	IC emission measurement stripline according to IEC 61967-8	
ICEM TEM	IC emission measurement according to TEM cell method IEC 61967-2	
ICIM DPI	IC immunity measurement direct power injection (DPI) acc. IEC 62132-4	
ICIM EFT	IC immunity measurement line conducted according to IEC 62215-3 and IEC 61000-4-4	
ICIM ESD	IC immuntity measurement line conducted according to IEC 61000-4-2 (HMM)	
ICIM field	IC immunity measurement field coupled analysis	
ICIM L-EFT	IC immunity measurement conductive coupling Lang- er EFT pulses	
ICIM SL	IC immunity measurement stripline according to IEC 62132-8	
ICIM TEM	IC immunity measurement TEM cell method according to IEC 62132-2	



For an offer, please contact Mrs. Susanne Kaule of Langer EMV-Technik GmbH.

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